

## Product Summary

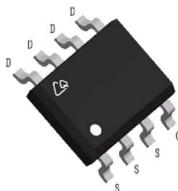
## Description and Applications

V(BR)DSS	RDS(ON) max	ID max
-30V	<6.4mΩ @ VGS = -10V	-20A
	<9.6mΩ @ VGS = -4.5V	

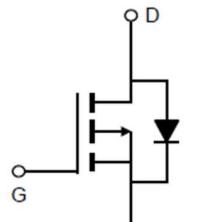
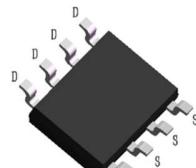
The CQS21305P uses advanced trench MOS technology to provide extremely low RDS(ON) and high current capability, this device is suitable for use as load switch and battery protection charge/discharge applications.

RoHS and Halogen-Free Compliant.

## View and Internal Schematic Diagram



SO8



Internal Schematic

## Marking Information



NOTE:  
 LOGO - CQAOS  
 21305P - Part number coder  
 F - Fab location code  
 A - Assembly location code  
 Y - Year code  
 W - Week code  
 L&T - Assembly lot code

## Ordering Information

Part Number	Case	Packaging
CQS21305P	SO8	3,000/Tape & Reel

## Maximum Ratings (@TA = +25°C unless otherwise specified.)

Parameters	Symbol	Max	Units
Drain-Source Voltage	VDSS	-30	V
Gate-Source Voltage	VGSS	±20	V
Continuous Drain Current	ID	-20 -14	A
Pulsed Drain Current <sup>C</sup>	IDM	-300	A
Power Dissipation <sup>B</sup>	PD	3.1 2	W
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>G</sub>	-55 to +150	°C

**Thermal Characteristics**

Characteristic		Symbol	Typ	Max	Unit
Maximum Junction-to-Ambient A	t ≤ 10s	$R_{\theta JA}$	29	40	°C/W
Maximum Junction-to-Ambient A D	Steady-State		60	75	°C/W
Maximum Junction-to-Lead	Steady-State	$R_{\theta JL}$	14	24	°C/W

**Electrical Characteristics (@TA = +25°C unless otherwise specified.)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
BVDSS	Drain-Source Breakdown Voltage	ID=-250μA, VGS=0V	-30			V
IDSS	Zero Gate Voltage Drain Current	VDS=-30V, VGS=0V			-1	μA
		TJ=55°C			-5	
IGSS	Gate-Body leakage current	VDS=0V, VGS= ±20V			±100	nA
VGS(th)	Gate Threshold Voltage	VDS=VGS ID=-250μA	-1	-1.45	-2	V
RDS(ON)	Static Drain-Source On-Resistance	VGS=-10V, ID=-20A		3.6	6.4	mΩ
		TJ=125°C		4.9	9	
		VGS=-4.5V, ID=-20A		5	9.6	
gFS	Forward Trans conductance	VDS=-5V, ID=-20A		72		S
VSD	Diode Forward Voltage	IS=-1A, VGS=0V		-0.7	-1	V
IS	Maximum Body-Diode Continuous Current				-4.4	A
<b>DYNAMIC PARAMETERS</b>						
Ciss	Input Capacitance	VGS=0V, VDS=-15V, f=1MHz		5418		pF
Coss	Output Capacitance			694		pF
Crss	Reverse Transfer Capacitance			466		pF
Rg	Gate resistance	VGS=0V, VDS=0V, f=1MHz	2.6	4	7	Ω
<b>SWITCHING PARAMETERS</b>						
Qg	Total Gate Charge	VGS=-10V, VDS=-15V, ID=-20A		104		nC
Qgs	Gate Source Charge			18		nC
Qgd	Gate Drain Charge			21		nC
tD(on)	Turn-On Delay Time	VGS=-10V, VDS=-15V, RL=0.75Ω, RGEN=3Ω		12		ns
tr	Turn-On Rise Time			79		ns
tD(off)	Turn-Off Delay Time			128		ns
tf	Turn-Off Fall Time			81		ns
trr	Body Diode Reverse Recovery Time	IF=-20A, dl/dt=100A/μs		26		ns
Qrr	Body Diode Reverse Recovery Charge	IF=-20A, dl/dt=100A/μs		12		nC

A. The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 1oz. Copper, in a still air environment with  $T_A=25^\circ C$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(MAX)}=150^\circ C$ , using  $\leq 10s$  junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(MAX)}=150^\circ C$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ C$ .

D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 1oz. Copper, assuming a maximum junction temperature of  $T_{J(MAX)}=150^\circ C$ . The SOA curve provides a single pulse rating.

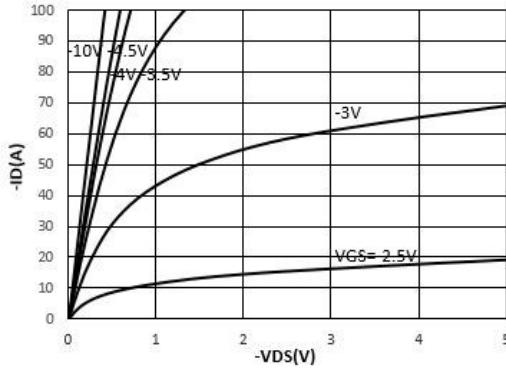
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Figure 1: On-Region Characteristics (Note E)

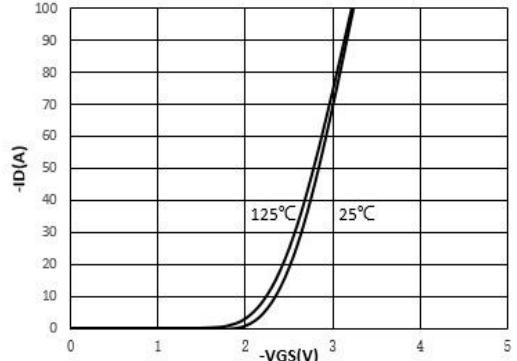


Figure 2 Transfer Characteristics (Note E)

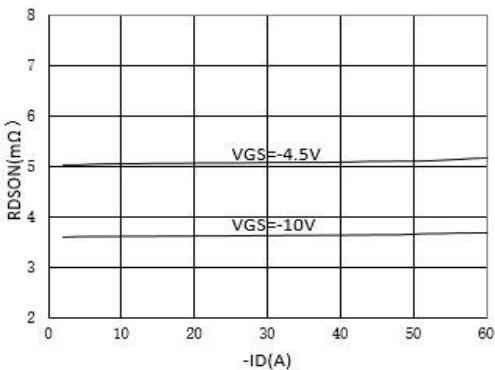


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

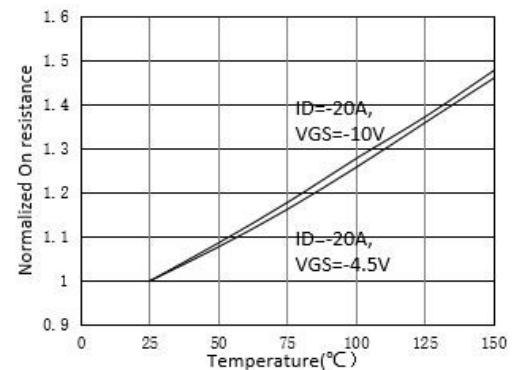


Figure 4: On-Resistance vs. Junction Temperature (Note E)

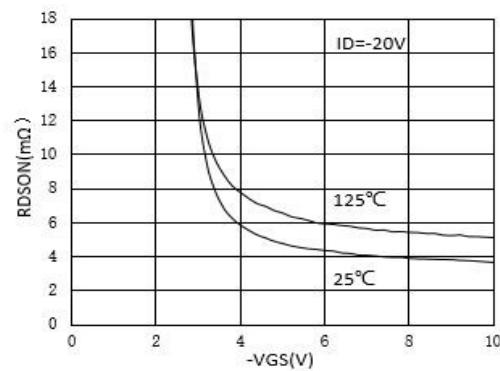


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

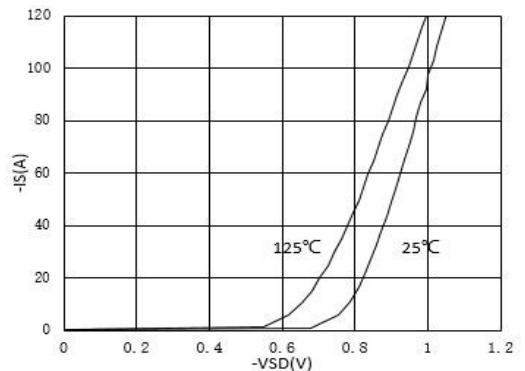


Figure 6: Body-Diode Characteristics (Note E)

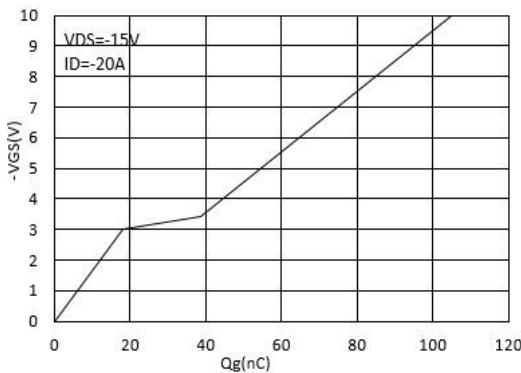


Figure 7: Gate-Charge Characteristics

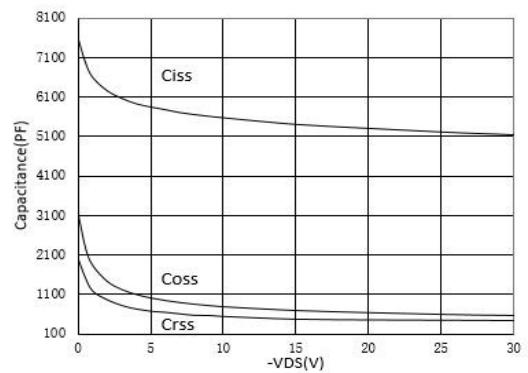


Figure 8: Capacitance Characteristics

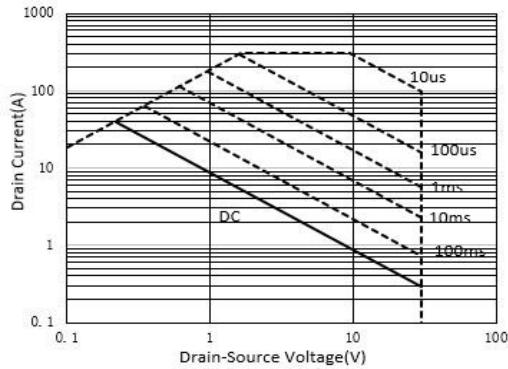


Figure 9: Maximum Forward Biased Safe Operating Area

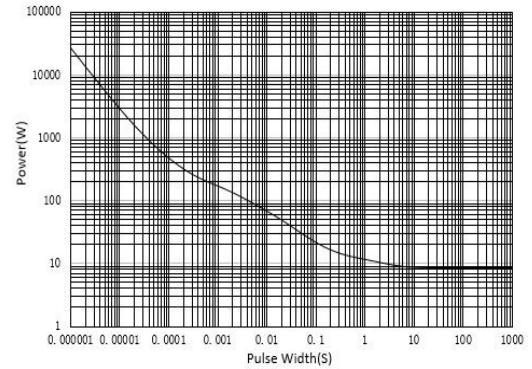


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

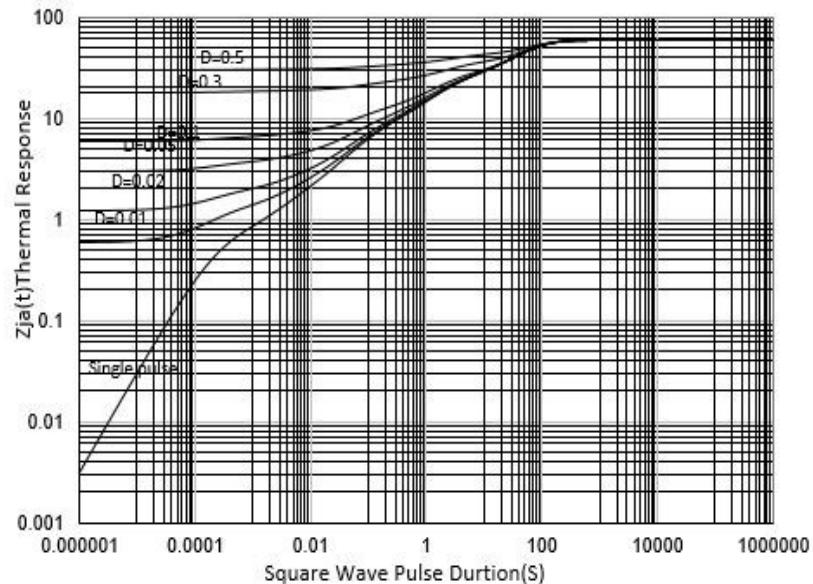


Figure 11: Normalized Maximum Transient Thermal Impedance (Note E)

单击下面可查看定价，库存，交付和生命周期等信息

[\*\*>>CQAOS\*\*](#)